











bq27621-G1

ZHCSCF1C - DECEMBER 2013 - REVISED APRIL 2014

bq27621-G1 系统侧电量计, 支持动态电压关联

特性

- 单节串联锂离子电池电量计
 - 驻留在系统主板上
 - 支持嵌入式或可拆除电池
 - 由具有集成低压降稳压器 (LDO) 的电池直接供
- 根据动态电压关联算法轻松配置电量计量
 - 用平滑滤波器报告剩余电量和充电状态 (SOC)
 - 针对自放电、温度和速率变化进行自动调节
- 微控制器外设支持:
 - 400kHz I²C 串口
 - 可配置 SOC 中断或 电池低数字输出报警
 - 内部温度传感器或 主机报告的温度
- 支持 4.2V, 4.3V 和 4.35V 化学成分电池
- 9 引脚 1.62mm x 1.58mm, 焊球间距 0.5mm YZF 封装

2 应用范围

- 智能手机、功能型手机和平板电脑
- 数码相机与数码摄像机
- 手持终端设备
- MP3 或多媒体播放器

3 说明

德州仪器 (TI) bq27621-G1 是一款易于配置的微控制 器外设,此外设提供针对单节锂离子电池的系统侧电量 计量。 此器件要求最小用户配置和系统微控制器固件 开发。

bo27621-G1 使用动态电压关联算法实现电量计量。 这一过程在计算剩余电量 (mAh), 充电状态 (%), 电池 电压 (mV) 和温度 (°C) 时无需感测电阻器。

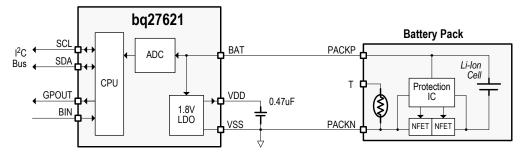
使用 bq27621-G1 进行电池电量计量只需将 PACK+ (P+) 与 PACK- (P-) 连接至可拆卸电池组或嵌入式电池 电路。 微型 9 引脚, 1.62mm x 1.58mm, 0.5mm 焊 球间距 YZF 封装非常适合于空间受限应用。

器件信息(1)

器件名称	封装	封装尺寸
BQ27621-G1	YZF	1.62mm x 1.58mm

(1) 要了解所有可用封装,请见数据表末尾的可订购产品附录。

典型应用





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修订历中记录		

5 修订历史记录

Ch	anges from Revision B (January 2014) to Revision C	Page
,	已更新命令列表和算法说明。	1
•	Updated BIN pin description	
•	Updated GPOUT pin description	3
Ch	anges from Revision A (January 2014) to Revision B	Page
,	Changed the I _{lkg} Parameters.Split out the GPOUT pin	<u>5</u>
Ch	nanges from Original (November 2013) to Revision A	Page
,	已将器件状态从:产品预览改为:生产	1
,	已将特性从:。。。。芯片级封装 (CSP) 更改为: YZF 封装	1
,	已将说明从: CSP 封装更改为: 。。。YZF 封装	1
,	Deleted Note 2 From the SUPPLY CURRENT table - "Wake Comparator Disabled"	4

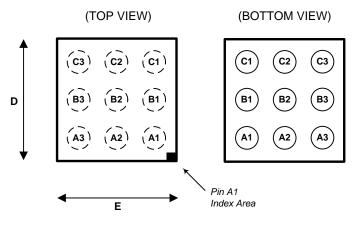


Device Comparison Table

PART NUMBER	BATTERY TYPE	CHEM_ID	FIRMWARE VERSION (2)	PACKAGE	COMMUNICATION FORMAT
	LiCoO ₂ (4.2 V maximum charge)	0x1202			
bq27621YZFR-G1	LiCoO ₂ (4.3 V maximum charge)	0x1210	1.05 (0x0105)	CSP-9	I ² C
	LiCoO ₂ (4.35 V maximum charge)	0x354			

- (1) See the CHEM_ID subcommand to confirm the battery chemistry type. See Alternate Chemistry Selection to select different chemistries.
- (2) See the FW_VERSION subcommand to confirm the firmware version.
- (3) For the most current package and ordering information see the Package Option Addendum at the end of this document; or, see the TI website at www.ti.com.

6 Pin Configurations and Functions



DIM	MIN	TYP	MAX	UNITS
D	1550	1580	1610	um
E	1590	1620	1650	μm

Pin Functions

Р	IN	TYPE ⁽¹⁾	DESCRIPTION		
NAME			DESCRIPTION		
BAT	AT C2, C3 PI, AI LDO regulator input and battery voltage input. Connect to positive battery connector. For highest accuracy, use a Kelvin connection by directly routing to the PACK+ pin and minimizing current flow through the trace.				
BIN	B1	DI	Battery insertion detection input. If <i>Operation Configuration</i> bit <i>[BIE]</i> = 1 (default), a logic low on the pin is detected as battery insertion. For a removable pack, the BIN pin can be connected to V_{SS} through a pulldown resistor on the pack, typically the $10\text{-k}\Omega$ thermistor; the system board should use a $1.8\text{-M}\Omega$ pullup resistor to V_{DD} to ensure the BIN pin is high when a battery is removed. If the battery is embedded in the system, it is recommended to leave <i>[BIE]</i> = 1 and use a $10\text{-k}\Omega$ pulldown resistor from BIN to V_{SS} . If $[BIE]$ = 0, then the host must inform the gauge of battery insertion and removal with the BAT_INSERT and BAT_REMOVE subcommands. A $10\text{-k}\Omega$ pulldown resistor should be placed between BIN and V_{SS} , even if this pin is unused. NOTE: The BIN pin must not be shorted directly to V_{CC} or V_{SS} and any pullup resistor on the BIN pin must be connected only to the bq27621 V_{DD} and not an external voltage rail.		
GPOUT	A1	DO	This open-drain output can be configured to indicate BAT_LOW when the <i>Operation Configuration [BATLOWEN]</i> bit is set. By default <i>[BATLOWEN]</i> is cleared and this pin performs an interrupt function (SOC_INT) by pulsing for specific events, such as a change in State of Charge. Signal polarity for these functions is controlled by the <i>[GPIOPOL]</i> configuration bit. This pin should not be left floating, even if unused, so a 10-k Ω pullup resistor is recommended.		
SCL	А3	DIO	Slave I ² C serial communications clock input line for communication with system (Master). Use with 10-kΩ pullup resistor (typical).		
SDA	A2	DIO	Slave I ² C serial communications data line for communication with system (Master). Open-drain I/O. Use with 10-kΩ pullup resistor (typical).		
VDD	В3	PO	1.8-V Regulator Output. Decouple with 0.47-µF ceramic capacitor to V _{SS} .		

(1) IO = Digital input-output, IA = Analog input, P = Power connection



Pin Functions (continued)

Р	PIN		DESCRIPTION
NAME NO.		TYPE ⁽¹⁾	DESCRIPTION
VSS	B2, C1	PI	Ground pins. B2 is the actual device ground pin while C1 is floating internally. Therefore, C1 may be used as a bridge to connect to the board ground plane without requiring a via under the device package. Recommend routing B2 to C1 using a top-layer metal trace on the board. Connect to negative battery connector. For highest accuracy, use a Kelvin connection by directly routing to the PACK– pin and minimizing current flow through the trace.

7 Electrical Specifications

7.1 Absolute Maximum Ratings

over operating free-air temperature range (unless otherwise noted) (1)

	PARAMETER	MIN	MAX	UNIT
V _{BAT}	BAT pin input voltage range	-0.3	6	V
V_{DD}	V _{DD} pin supply voltage range (LDO output)	-0.3	2	V
V _{IOD}	Open-drain I/O pins (SDA, SCL, GPOUT)	-0.3	6	V
V _{IOPP}	Push-Pull I/O pins (BIN)	-0.3	[V _{DD} + 0.3]	V
T _A	Operating free-air temperature range	-40	85	°C

⁽¹⁾ Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

7.2 Handling Ratings

			MIN	MAX	UNIT
T _{stg} Storage temperature range		ne e	- 65	150	°C
V	Electrostatic discharge	Human body model (HBM), per ANSI/ESDA/JEDEC JS-001, all pins ⁽¹⁾	-1	1	kV
V _(ESD)	Electrostatic discharge	Charged device model (CDM), per JEDEC specification JESD22-C101, all pins (2)	-250	250	V

- (1) JEDEC document JEP155 states that 500-V HBM allows safe manufacturing with a standard ESD control process.
- (2) JEDEC document JEP157 states that 250-V CDM allows safe manufacturing with a standard ESD control process.

7.3 Recommended Operating Conditions

 $T_A = 30$ °C and $V_{REGIN} = V_{BAT} = 3.6 \text{ V}$ (unless otherwise noted)

_^	REGIN BAT	· · · · · · · · · · · · · · · · · · ·				
	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
C _{BAT} ⁽¹⁾	Optional external input capacitor for internal LDO between BAT and $\ensuremath{\text{V}_{\text{SS}}}$	Nominal capacitor values specified.		0.1		μF
C _{LDO18} (1)	External output capacitor for internal LDO between V _{DD} and V _{SS}	Recommend a 5% ceramic X5R type capacitor located close to the device.		0.47		μF
V _{PU} (1)	External pullup voltage for open-drain pins (SDA, SCL, GPOUT)		1.62		3.6	V

⁽¹⁾ Specified by design. Not production tested.

7.4 Thermal Information

over operating free-air temperature range (unless otherwise noted)

	THERMAL METRIC ⁽¹⁾	bq27621-G1	LINUT
	THERMAL METRIC	YZF (9 PINS)	UNIT
$R_{\theta JA}$	Junction-to-ambient thermal resistance	107.8	
R ₀ JC(top)	Junction-to-case (top) thermal resistance	0.7	
$R_{\theta JB}$	Junction-to-board thermal resistance	60.4	8CAA/
ΨЈТ	Junction-to-top characterization parameter	3.5	°C/W
ΨЈВ	Junction-to-board characterization parameter	60.4	
R _{0JC(bot)}	Junction-to-case (bottom) thermal resistance	n/a	

⁽¹⁾ For more information about traditional and new thermal metrics, see the IC Package Thermal Metrics application report, SPRA953



7.5 Supply Current

 $T_A = 30$ °C and $V_{REGIN} = V_{BAT} = 3.6 \text{ V}$ (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
I _{CC} (1)	NORMAL mode current	I _{LOAD} > Sleep Current		27		μΑ
I _{SLP} (1)	SLEEP mode current	I _{LOAD} < Sleep Current		21		μΑ
I _{HIB} ⁽¹⁾	HIBERNATE mode current	I _{LOAD} < Hibernate Current		9		μA
I _{SD} ⁽¹⁾	SHUTDOWN mode current	Fuel gauge in host commanded SHUTDOWN mode. (LDO Regulator Output Disabled)		0.6		μΑ

⁽¹⁾ Specified by design. Not production tested.

7.6 Digital Input and Output DC Characteristics

 $T_A = -40$ °C to 85°C, typical values at $T_A = 30$ °C and $V_{REGIN} = 3.6$ V (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
V _{IH(OD)}	Input voltage, high (2)	External pullup resistor to V _{PU}	$V_{PU} \times 0.7$			V
V _{IL}	Input voltage, low (2) (3)				0.6	V
V _{OL}	Output voltage, low (2)				0.6	V
I _{OH}	Output source current, high (2)				0.5	mA
I _{OL(OD)}	Output sink current, low (2)				-3	mA
C _{IN} (1)	Input capacitance (2) (3)				5	рF
I _{lkg}	Input leakage current (SCL, SDA, BIN)				0.1	μA
9	Input leakage current (GPOUT)				1	•

⁽¹⁾ Specified by design. Not production tested.

7.7 LDO Regulator, Wake-up, and Auto-Shutdown DC Characteristics

 $T_A = -40$ °C to 85°C, typical values at $T_A = 30$ °C and $V_{REGIN} = 3.6$ V (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
V_{BAT}	BAT pin regulator input		2.45		4.5	V
V_{DD}	Regulator output voltage			1.8		V
UVLO _{IT+}	V _{BAT} Under Voltage Lock Out LDO Wake-Up Rising Threshold			2		V
UVLO _{IT}	V _{BAT} Under Voltage Lock Out LDO Auto-Shutdown Falling Threshold			1.95		V

⁽¹⁾ Specified by design. Not production tested.

7.8 ADC (Temperature and Cell Measurement) Characteristics

 $T_A = -40$ °C to 85°C; typical values at $T_A = 30$ °C and $V_{REGIN} = 3.6$ V (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
V _{IN(BAT)}	BAT pin voltage measurement range.	Voltage divider enabled.	2.45		4.5	V
t _{ADC_CONV}	Conversion time			125		ms
	Effective Resolution			15		bits

⁽¹⁾ Specified by design. Not tested in production.

Open drain pins: (SCL, SDA, GPOUT)

⁽²⁾ Open drain pins: (Si (3) Push-pull pin: (BIN)



7.9 I²C-Compatible Interface Communication Timing Characteristics

 $T_A = -40$ °C to 85°C; typical values at $T_A = 30$ °C and $V_{REGIN} = 3.6$ V (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
Standard M	ode (100 kHz)					
t _{d(STA)}	Start to first falling edge of SCL		4			μs
t _{w(L)}	SCL pulse duration (low)		4.7			μs
t _{w(H)}	SCL pulse duration (high)		4			μs
t _{su(STA)}	Setup for repeated start		4.7			μs
t _{su(DAT)}	Data setup time	Host drives SDA	250			ns
t _{h(DAT)}	Data hold time	Host drives SDA	0			ns
t _{su(STOP)}	Setup time for stop		4			μs
t _(BUF)	Bus free time between stop and start	Includes Command Waiting Time	66			μs
t _f	SCL/SDA fall time (1)				300	ns
t _r	SCL/SDA rise time (1)				300	ns
f _{SCL}	Clock frequency ⁽²⁾				100	kHz
Fast Mode ((400 kHz)					
t _{d(STA)}	Start to first falling edge of SCL		600			ns
t _{w(L)}	SCL pulse duration (low)		1300			ns
t _{w(H)}	SCL pulse duration (high)		600			ns
t _{su(STA)}	Setup for repeated start		600			ns
t _{su(DAT)}	Data setup time	Host drives SDA	100			ns
t _{h(DAT)}	Data hold time	Host drives SDA	0			ns
t _{su(STOP)}	Setup time for stop		600			ns
t _(BUF)	Bus free time between stop and start	Includes Command Waiting Time	66			μs
t _f	SCL/SDA fall time (1)				300	ns
t _r	SCL/SDA rise time (1)				300	ns
f _{SCL}	Clock frequency ⁽²⁾				400	kHz

- (1) Specified by design. Not production tested.
- (1) Opcomined by design. Not production tested.
 (2) If the clock frequency (f_{SCL}) is > 100 kHz, use 1-byte write commands for proper operation. All other transactions types are supported at 400 kHz. (Refer to I²C Interface and I²C Command Waiting Time)

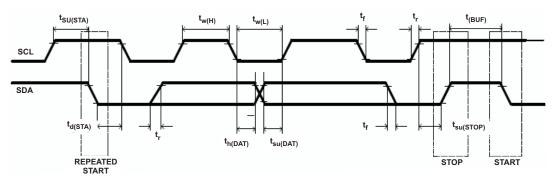


Figure 1. I²C-Compatible Interface Timing Diagrams



8 Detailed Description

8.1 Overview

The bq27621-G1 battery fuel gauge accurately predicts the battery capacity and other operational characteristics of a single Li-based rechargeable cell. It can be interrogated by a system processor to provide cell information such as **State of Charge** (%) and **Remaining Capacity** (mAh). The device is preconfigured with three battery profiles. The default profile is for standard LiCoO₂-based batteries with a maximum charge voltage of 4.2 V. The other two profiles that can be selected via I²C commands are for batteries with charging voltages of 4.3 V and 4.35 V.

Unlike some other fuel gauges, the bq27621-G1 fuel gauge can not be programmed with specific battery chemistry profiles. For many battery types and applications, the predefined standard chemistry profiles available in the bq27621-G1 fuel gauge are sufficient matches from a gauging perspective.

Information is accessed through a series of commands, called *Standard Commands*. Further capabilities are provided by the additional *Extended Commands* set. Both sets of commands, indicated by the general format *Command()*, are used to read and write information contained within the control and status registers, as well as its data locations. Commands are sent from system to gauge using the I²C serial communications engine, and can be executed during application development, system manufacture, or end-equipment operation.

The key to the fuel gauging prediction of the bq27621-G1 fuel gauge is Texas Instruments proprietary Dynamic Voltage Correlation algorithm. This algorithm eliminates the need for a sense resistor when calculating remaining battery capacity (mAh) and state-of-charge (%). This algorithm uses cell voltage measurements and cell characteristics to create state-of-charge predictions that can achieve high accuracy across a wide variety of operating conditions.

The fuel gauge estimates charge and discharge activity by monitoring the cell voltage. Cell impedance is computed based on estimated current, open-circuit voltage (OCV), and cell voltage under loaded conditions.

The fuel gauge uses an integrated temperature sensor for estimating cell temperature. Alternatively, the system processor can provide temperature data for the fuel gauge.

To minimize power consumption, the fuel gauge has several power modes: INITIALIZATION, NORMAL, SLEEP, HIBERNATE, and SHUTDOWN. The fuel gauge passes automatically between these modes, depending upon the occurrence of specific events, though a system processor can initiate some of these modes directly.

The gauge can be configured and used in a matter of minutes by following the *Quickstart Guide for bq27621-G1* (SLUUAP5). The information in that document is sufficient for most applications. For further customization and options, more exhaustive details can be found in the *bq27621-G1 Technical Reference Manual* (SLUUAD4).

NOTE

Formatting conventions used in this document:

Commands: *italics* with *parentheses* and no breaking spaces, for example: RemainingCapacity()

Data Memory Configuration Parameter: *italics*, **bold**, and *breaking spaces*, for example: **Design Capacity**

Register bits and flags: brackets and italics, for example: [ITPOR]

Data Memory Configuration Parameter bits: brackets, italics and bold, for example: [BIE]

Modes and states: ALL CAPITALS, for example: UNSEALED mode



8.2 Feature Description

8.2.1 Data Commands

8.2.1.1 Standard Data Commands

The bq27621-G1 uses a series of 2-byte standard commands to enable system reading and writing of battery information. Each standard command has an associated command-code pair, as indicated in Table 1. Because each command consists of two bytes of data, two consecutive I²C transmissions must be executed both to initiate the command function, and to read or write the corresponding two bytes of data. Additional details are found in the bq27621-G1 Technical Reference Manual (SLUUAD4).

NOTE

Data values read by the host may be invalid during initialization for a period of up to 3 seconds.

Table 1. Standard Commands

NAME		COMMAND CODE	UNIT	SEALED ACCESS
Control()	CNTL	0x00 and 0x01	NA	R/W
Temperature()	TEMP	0x02 and 0x03	0.1°K	R/W
Voltage()	VOLT	0x04 and 0x05	mV	R
Flags()	FLAGS	0x06 and 0x07	NA	R
NominalAvailableCapacity()		0x08 and 0x09	mAh	R
FullAvailableCapacity()		0x0A and 0x0B	mAh	R
RemainingCapacity()	RM	0x0C and 0x0D	mAh	R
FullChargeCapacity()	FCC	0x0E and 0x0F	mAh	R
EffectiveCurrent()		0x10 and 0x11	mA	R
AveragePower()		0x18 and 0x19	mW	R
StateOfCharge()	SOC	0x1C and 0x1D	%	R
InternalTemperature()		0x1E and 0x1F	0.1°K	R
RemainingCapacityUnfiltered()		0x28 and 0x29	mAh	R
RemainingCapacityFiltered()		0x2A and 0x2B	mAh	R
FullChargeCapacityUnfiltered()		0x2C and 0x2D	mAh	R
FullChargeCapacityFiltered()		0x2E and 0x2F	mAh	R
StateOfChargeUnfiltered()		0x30 and 0x31	mAh	R
OperationConfiguration()		0x3A and 0x3B	NA	R



8.2.1.2 Control(): 0x00 and 0x01

Issuing a *Control()* command requires a subsequent 2-byte subcommand. These additional bytes specify the particular control function desired. The *Control()* command allows the system to control specific features of the fuel gauge during normal operation and additional features when the device is in different access modes. Additional details are found in the *bq27621-G1 Technical Reference Manual (SLUUAD4)*.

Table 2. Control() Subcommands

CNTL FUNCTION	CNTL DATA	SEALED ACCESS	DESCRIPTION
CONTROL_STATUS	0x0000	Yes	Reports the status of device.
DEVICE_TYPE	0x0001	Yes	Reports the device type (0x0621).
FW_VERSION	0x0002	Yes	Reports the firmware version of the device.
PREV_MACWRITE	0x0007	Yes	Returns previous MAC command code.
CHEM_ID	8000x0	Yes	Reports the chemical identifier of the battery profile currently used by the fuel gauging algorithm
BAT_INSERT	0x000C	Yes	Forces the [BAT_DET] bit set when the [BIE] bit is 0.
BAT_REMOVE	0x000D	Yes	Forces the [BAT_DET] bit clear when the [BIE] bit is 0.
TOGGLE_POWERMIN	0x0010	Yes	Set CONTROL_STATUS [POWERMIN] to 1.
SET_HIBERNATE	0x0011	Yes	Forces CONTROL_STATUS [HIBERNATE] to 1.
CLEAR_HIBERNATE	0x0012	Yes	Forces CONTROL_STATUS [HIBERNATE] to 0.
SET_CFGUPDATE	0x0013	No	Force CONTROL_STATUS [CFGUPMODE] to 1 and gauge enters CONFIG UPDATE mode.
SHUTDOWN_ENABLE	0x001B	No	Enables device SHUTDOWN mode.
SHUTDOWN	0x001C	No	Commands the device to enter SHUTDOWN mode.
SEALED	0x0020	No	Places the device in SEALED access mode.
TOGGLE_GPOUT	0x0023	Yes	Test the GPIO pin by sending a pulse signal
ALT_CHEM1	0x0031	No	Selects alternate chemistry 1 (0x1210)
ALT_CHEM2	0x0032	No	Selects alternate chemistry 2 (0x354)
RESET	0x0041	No	Performs a full device reset.
SOFT_RESET	0x0042	No	Gauge exits CONFIG UPDATE mode.
EXIT_CFGUPDATE	0x0043	No	Exits CONFIG UPDATE mode without an OCV measurement and without resimulating to update StateOfCharge().
EXIT_RESIM	0x0044	No	Exits CONFIG UPDATE mode without an OCV measurement and resimulates with the updated configuration data to update StateOfCharge().

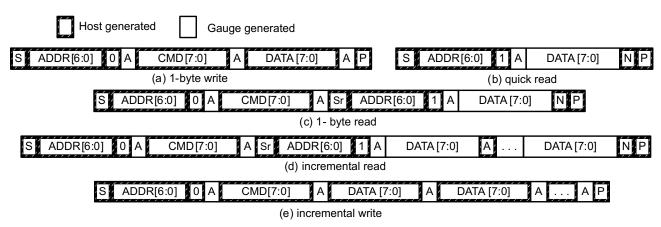
8.2.2 Alternate Chemistry Selection

The fuel gauge allows the user to change the chemistry settings using I²C commands. The default chemistry has a CHEM_ID of 0x1202. The two other CHEM_IDs supported by this device includes CHEM_ID 0x1210 and CHEM_ID 0x354. The detailed procedure to change the chemistry is available in the *bq27621-G1 Technical Reference Manual (SLUUAD4)*.

8.2.3 I²C Interface

The bq27621-G1 fuel gauge supports the standard I²C read, incremental read, quick read, one-byte write, and incremental write functions. The 7-bit device address (ADDR) is the most significant 7 bits of the hex address and is fixed as 1010101. The first 8 bits of the I²C protocol are, therefore, 0xAA or 0xAB for write or read, respectively.



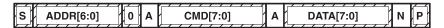


(S = Start, Sr = Repeated Start, A = Acknowledge, N = No Acknowledge, and P = Stop).

The quick read returns data at the address indicated by the address pointer. The address pointer, a register internal to the I^2C communication engine, increments whenever data is acknowledged by the fuel gauge or the I^2C master. The quick writes function in the same manner and are a convenient means of sending multiple bytes to consecutive command locations (such as two-byte commands that require two bytes of data).

The following command sequences are not supported:

Attempt to write a read-only address (NACK after data sent by master):



Attempt to read an address above 0x6B (NACK command):



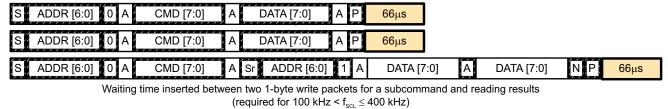
8.2.4 I2C Time Out

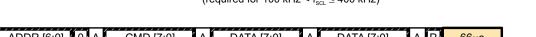
The I²C engine releases both SDA and SCL if the I²C bus is held low for 2 seconds. If the fuel gauge is holding the lines, releasing them frees them for the master to drive the lines.

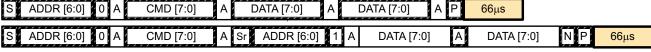


8.2.5 I²C Command Waiting Time

To ensure proper operation at 400 kHz, a $t_{(BUF)} \ge 66$ µs bus-free waiting time must be inserted between all packets addressed to the fuel gauge. In addition, if the SCL clock frequency (f_{SCL}) is > 100 kHz, use individual 1-byte write commands for proper data flow control. The following diagram shows the standard waiting time required between issuing the control subcommand the reading the status result. For read-write standard command, a minimum of 2 seconds is required to get the result updated. For read-only standard commands, there is no waiting time required, but the host must not issue any standard command more than two times per second. Otherwise, the gauge could result in a reset issue due to the expiration of the watchdog timer.







Waiting time inserted between incremental 2-byte write packet for a subcommand and reading results (acceptable for $f_{SCI} \le 100 \text{ kHz}$)



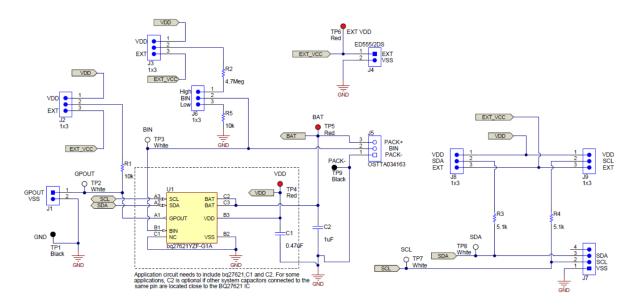
Waiting time inserted after incremental read

8.2.6 I²C Clock Stretching

A clock stretch of up to 4 ms can occur during all modes of fuel gauge operation. In SLEEP and HIBERNATE modes, a short clock stretch occurs on all I²C traffic as the device must wake-up to process the packet. In the other modes (INITIALIZATION, NORMAL) clock stretching only occurs for packets addressed for the fuel gauge. The majority of clock stretch periods are small as the I²C interface performs normal data flow control.



8.3 Reference (EVM) Schematic





9 Device and Documentation Support

9.1 Documentation Support

9.1.1 Related Documentation from Texas Instruments

To obtain a copy of any of the following TI documents, call the Texas Instruments Literature Response Center at (800) 477-8924 or the Product Information Center (PIC) at (972) 644-5580. When ordering, identify this document by its title and literature number. Updated documents also can be obtained through the TI Web site at www.ti.com.

- 1. bg27621-G1 Technical Reference User's Guide (SLUUAD4)
- 2. bq27621 EVM: Single-Cell Technology User's Guide (SLUUAM6)
- 3. Quickstart Guide for bg27621-G1 (SLUUAP5)

9.2 Trademarks

All trademarks are the property of their respective owners.

9.3 Electrostatic Discharge Caution



This integrated circuit can be damaged by ESD. Texas Instruments recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedures can cause damage.

ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications.

9.4 Glossary

SLYZ022 — TI Glossary.

This glossary lists and explains terms, acronyms and definitions.

10 Mechanical, Packaging, and Orderable Information

The following pages include mechanical packaging and orderable information. This information is the most current data available for the designated devices. This data is subject to change without notice and revision of this document. For browser-based versions of this data sheet, refer to the left-hand navigation.

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PACKAGING INFORMATION

Orderable part number	Status (1)	Material type	Package Pins	Package qty Carrier	RoHS	Lead finish/ Ball material	MSL rating/ Peak reflow	Op temp (°C)	Part marking (6)
BQ27621YZFR-G1A	Active	Production	DSBGA (YZF) 9	3000 LARGE T&R	Yes	SNAGCU	Level-1-260C-UNLIM	-40 to 85	BQ27621 G1A
BQ27621YZFR-G1A.A	Active	Production	DSBGA (YZF) 9	3000 LARGE T&R	Yes	SNAGCU	Level-1-260C-UNLIM	-40 to 85	BQ27621 G1A
BQ27621YZFT-G1A	Active	Production	DSBGA (YZF) 9	250 SMALL T&R	Yes	SNAGCU	Level-1-260C-UNLIM	-40 to 85	BQ27621 G1A
BQ27621YZFT-G1A.A	Active	Production	DSBGA (YZF) 9	250 SMALL T&R	Yes	SNAGCU	Level-1-260C-UNLIM	-40 to 85	BQ27621 G1A

⁽¹⁾ Status: For more details on status, see our product life cycle.

Multiple part markings will be inside parentheses. Only one part marking contained in parentheses and separated by a "~" will appear on a part. If a line is indented then it is a continuation of the previous line and the two combined represent the entire part marking for that device.

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⁽²⁾ Material type: When designated, preproduction parts are prototypes/experimental devices, and are not yet approved or released for full production. Testing and final process, including without limitation quality assurance, reliability performance testing, and/or process qualification, may not yet be complete, and this item is subject to further changes or possible discontinuation. If available for ordering, purchases will be subject to an additional waiver at checkout, and are intended for early internal evaluation purposes only. These items are sold without warranties of any kind.

⁽³⁾ RoHS values: Yes, No, RoHS Exempt. See the TI RoHS Statement for additional information and value definition.

⁽⁴⁾ Lead finish/Ball material: Parts may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

⁽⁵⁾ MSL rating/Peak reflow: The moisture sensitivity level ratings and peak solder (reflow) temperatures. In the event that a part has multiple moisture sensitivity ratings, only the lowest level per JEDEC standards is shown. Refer to the shipping label for the actual reflow temperature that will be used to mount the part to the printed circuit board.

⁽⁶⁾ Part marking: There may be an additional marking, which relates to the logo, the lot trace code information, or the environmental category of the part.



PACKAGE OPTION ADDENDUM

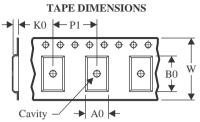
www.ti.com 31-Oct-2025

PACKAGE MATERIALS INFORMATION

www.ti.com 25-Sep-2024

TAPE AND REEL INFORMATION





A0	Dimension designed to accommodate the component width
В0	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE

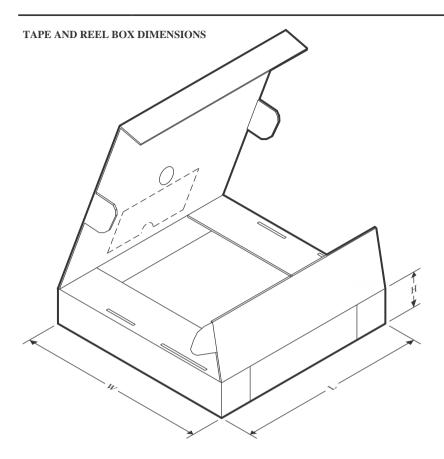


*All dimensions are nominal

Device	Package Type	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
BQ27621YZFR-G1A	DSBGA	YZF	9	3000	180.0	8.4	1.78	1.78	0.69	4.0	8.0	Q1
BQ27621YZFT-G1A	DSBGA	YZF	9	250	180.0	8.4	1.78	1.78	0.69	4.0	8.0	Q1

PACKAGE MATERIALS INFORMATION

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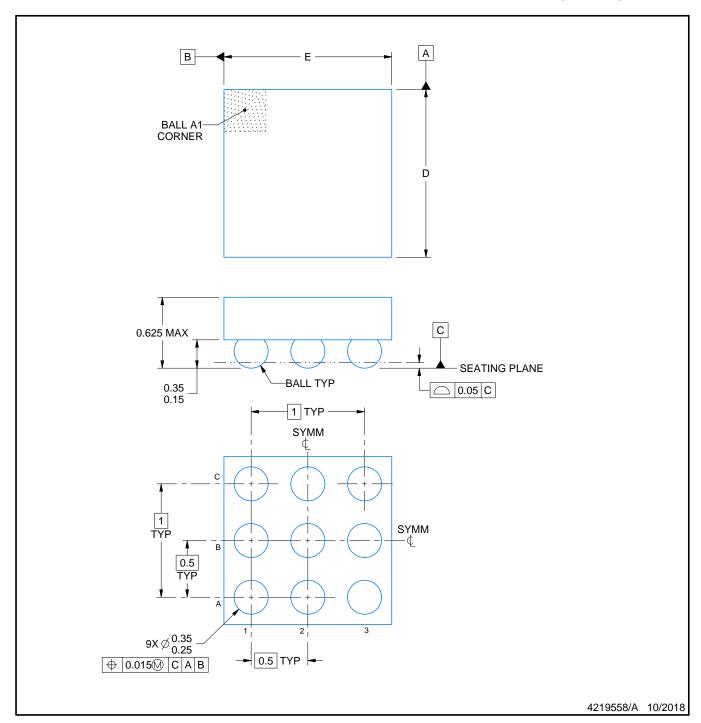


*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
BQ27621YZFR-G1A	DSBGA	YZF	9	3000	182.0	182.0	20.0
BQ27621YZFT-G1A	DSBGA	YZF	9	250	182.0	182.0	20.0



DIE SIZE BALL GRID ARRAY



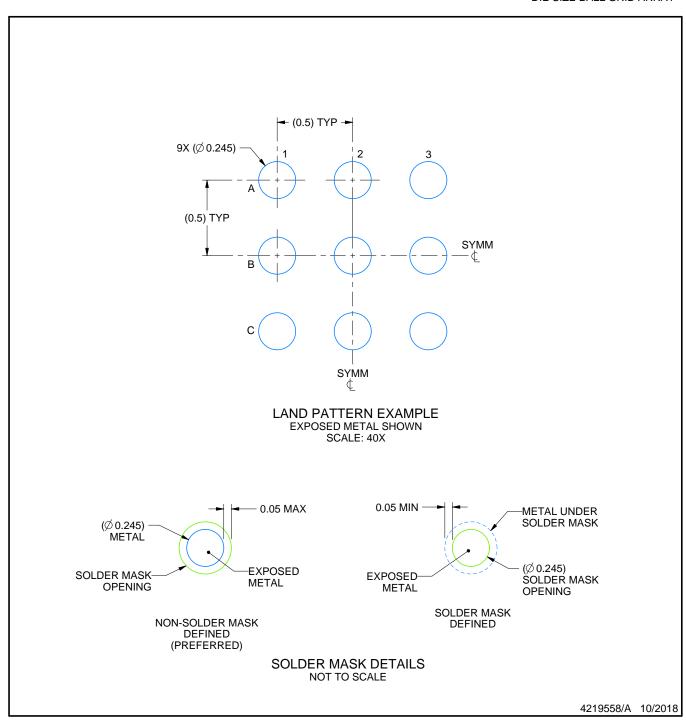
NOTES:

- 1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.

 2. This drawing is subject to change without notice.



DIE SIZE BALL GRID ARRAY

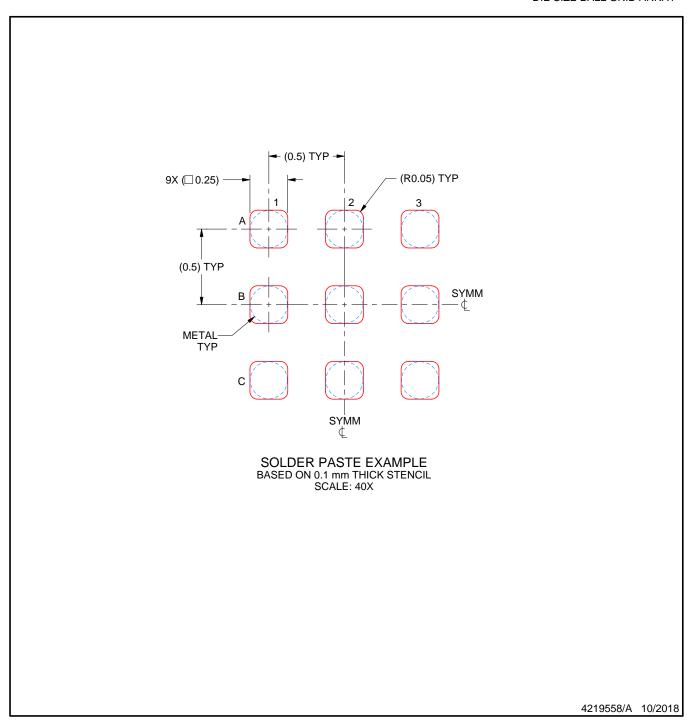


NOTES: (continued)

Final dimensions may vary due to manufacturing tolerance considerations and also routing constraints. See Texas Instruments Literature No. SNVA009 (www.ti.com/lit/snva009).



DIE SIZE BALL GRID ARRAY



NOTES: (continued)

4. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release.



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